PROCEEDINGS OF SPIE

Dimensional Optical Metrology and Inspection for Practical Applications IX

Kevin G. Harding Song Zhang Editors

27 April – 8 May 2020 Online Only, United States

Sponsored and Published by SPIE

Volume 11397

Proceedings of SPIE 0277-786X, V. 11397

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Author(s), "Title of Paper," in Dimensional Optical Metrology and Inspection for Practical Applications IX, edited by Kevin G. Harding, Song Zhang, Proceedings of SPIE Vol. 11397 (SPIE, Bellingham, WA, 2020) Seven-digit Article CID Number.

ISSN: 0277-786X ISSN: 1996-756X (electronic)

ISBN: 9781510635715 ISBN: 9781510635722 (electronic)

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Contents

OPTICAL METROLOGY METHODS I

- 11397 02 Improving the measurement robustness of active stereo 3D sensors by optimization of shifted aperiodic fringe patterns (Invited Paper) [11397-1]
- 11397 03 Extension of the registration possibilities and determination of the positioning precision of a multi-scale fringe projection system [11397-2]
- 11397 04 **3D high-resolution multimodal imaging system for real-time applications** [11397-3]
- 11397 05 Continuous low-latency 3D measurements using efficient freeform GOBO pattern projection and close-to-sensor image rectification [11397-4]

OPTICAL METROLOGY METHODS II

- 11397 07 High resolution flatness measurements on diffuse and scattering surfaces [11397-6]
- 11397 08 Uniaxial fringe projection profilometry using projection defocus [11397-7]

OPTICAL METROLOGY ANALYSIS I

- 11397 0A Similarity evaluation of 3D topological measurement results using statistical methods (Rising Researcher Paper) [11397-9]
- 11397 0D What is the best triangulation approach for a structured light system? [11397-12]
- 11397 OE **Distortion-free camera calibration** [11397-13]

OPTICAL METROLOGY APPLICATIONS

11397 0I Large part metrology challenges and lessons learned [11397-18]

POSTER SESSION

11397 0K Research of percolation at objects for waste disposal according to space image data [11397-20]